## Notice of References Cited Application/Control No. 10/724,951 Examiner Erin M. File Applicant(s)/Patent Under Reexamination CHAN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,849,711 A	07-1989	Leis et al.	330/279
*	В	US-2002/0080887 A1	06-2002	Jeong et al.	375/295
*	С	US-2003/0036361 A1	02-2003	Kawai et al.	455/69
*	D	US-2003/0060193 A1	03-2003	Kurita, Hiroyuki	455/423
*	Е	US-6,597,925 B1	07-2003	Garcia et al.	455/561
*	F	US-2004/0100921 A1	05-2004	Khan, Farooq Ullah	370/321
*	G	US-6,765,440 B2	07-2004	Chandrasekaran, Rajiv	330/149
*	Н	US-2004/0251962 A1	12-2004	Rosnell et al.	330/134
*	. 1	US-6,965,676 B1	11-2005	Allred, Rustin W	381/104
*	J	US-2006/0046658 A1	03-2006	Cruz et al.	455/067.11
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					·
	0					
	Р					
	Q				•	
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

	NON-FATENT DOCUMENTS							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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	w							
	x							

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